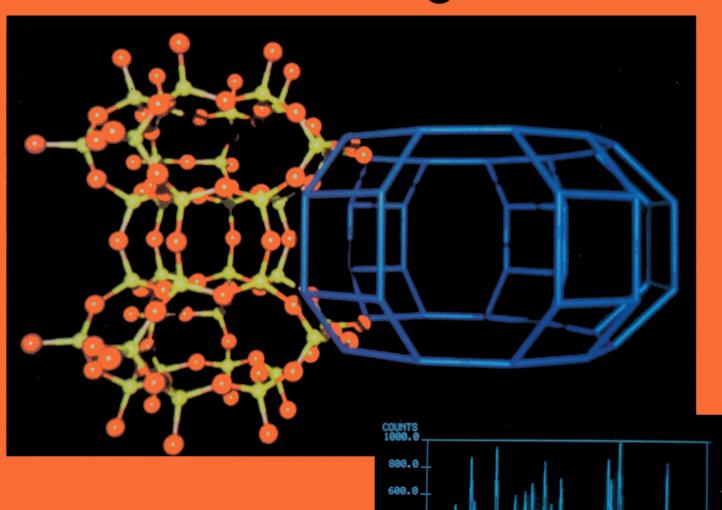
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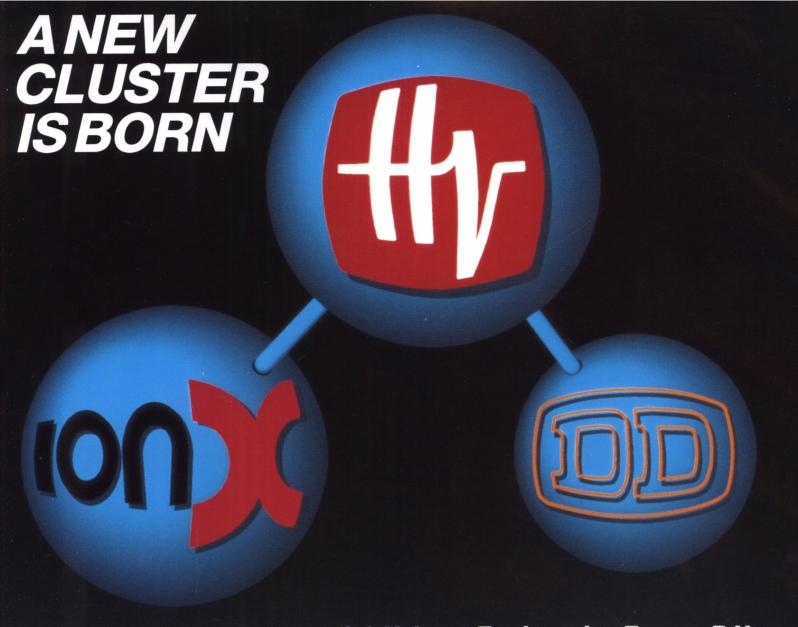
November 1990

Volume XV, Number 11

Serving the International Materials Research Community

Neutron Scattering





General lonex acquired by High Voltage Engineering Europa B.V.

In December 1987 High Voltage Engineering Europa B.V. (HVEE) acquired Dowlish Developments Ltd (DD), an accelerator tube manufacturer located in the United Kingdom.

On April 10, 1989, HVEE purchased the General Ionex Analytical Product Group from Genus Inc. based in the United States.

Through this acquisition HVEE positions itself as the largest and most diverse manufacturer of particle accelerators for the scientific and industrial research communities.

The acquired General Ionex (GI) product lines, which include the Tandetron accelerator systems and Model 4175 RBS Analyser, will be manufactured in HVEE's new, well-equipped facility in Amersfoort, The Netherlands.

World wide marketing of all products from HVEE, DD and GI will originate from HVEE Amersfoort with sales and service offices in the USA, Europe and Japan.

After addition of the newly acquired products HVEE's product lines include:

- Ion Accelerator Systems
 - Air insulated accelerators up to 500 kV
 - Single ended Van de Graaff accelerators up to 4 MV
 - Tandem Tandetron accelerators up to 3 MV/TV
- Research ion implanters
- Beam energies 10 keV-9 MeV and higher
- Systems for ion beam analysis
 - Systems for RBS, PIXE, PIGE, NRA, ERD, MACS and MEIS
- Components
 - HV power supplies, electron and ion accelerator tubes, ion sources beamline components, beam monitoring equipment, UHV sample manipulators, etc.

For further information on this transaction and product literature please contact HVEE in Amersfoort/NL.



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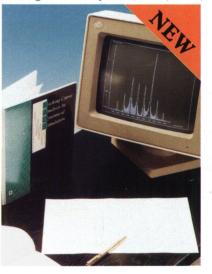
Triple Axis Attachment



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For further information on these and other products contact



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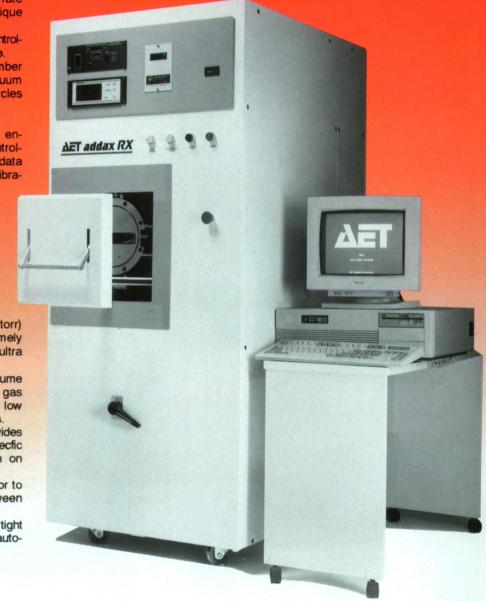
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November 1990

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ON THE COVER: Portion of the framework structure of zeolite L rendered by the OASIS program (Si/Al - vellow, O - red) with the channel lobe drawn as blue segments connecting adjacent Si/Al sites. The structure was refined by Rietveld analysis of powder neutron diffraction data measured on the H4S station of the Brookhaven High Flux Reactor. The plot shows a portion of the observed diffraction profile (dark blue), that calculated after structure optimization (light blue), and the difference between the two on the same scale (red). The central positions of the Bragg peaks that contribute to the pattern are indicated by the white tics. For details see "Neutron Powder Diffraction" by J.D. Jorgensen and J.M. Newsam on p. 49. (Figure courtesy of J.M. Newsam and W.L. Barrow.)

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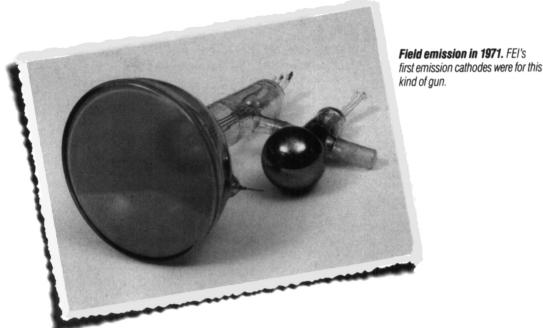
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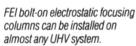
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